

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

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Schedule of Scope to Certificate of Conformity Approved Process

IECQ Certificate No.: IECQ-L ULTW 14.0003
CB Certificate No.: 20000171 ITL

Schedule Number: IECQ-L ULTW 14.0003-S Rev No.: 1 Revision Date: 2019/11/29 Page 1 of 2

Appendix-1 (20000171 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Decap (Normal type -Au wire)	AA0093
Decap (Normal type -Cu wire)	AA0093
Decap (Special type-BGA/PCB)	AA0093
Decap (Special type-Special Epoxy)	AA0093
Take crystalline grain	AA0093
Chip Delayer (De-Al layer experiment)	AA0093
Wafer Delayer (De-Al layer experiment)	AA0093
Remove Polyimide of Wafer	AA0093
Optical microscope observing	AD0286
Stereomicroscope observing	AD0295
Taking photo of IC	AD0295
IV Curve measuring	AD0316
SEM	AD0323
SEM-EDS (um grade)	AD0323
Cross Section (un-precision)	AA0093
Cross Section (precision)	AA0093
Rubber Test	AD0313

This schedule is only valid in conjunction with the referenced Certificate of Approval
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Bursting strength testing		AD0300	
Optical surface measurement system (Leica DCN and Interferometry Microscope)	18 Confocal	AD0345	
High pressure gas & risk gas particle measuring		AD0349	
FTIR Fourier-Transform Infrared spectroscopy an	alysis	AD0368	
Liquid Particle Counter (LPC) liquid particle meas	uring	AD0366	
Ion Chromatography analysis		AD0335	

Technical Reviewer of DQS: Michael Chou Date: 11/29/2019



